

G-RAD Workshop - Grenoble Radiation Testing of semiconductor devices and systems



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Laser testing as an optimized complement of Heavy Ion for SEE testing - experiences from Airbus DS

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Pulsed-laser approaches have demonstrated to be a very interesting tool for SEE testing and offers a great complementarity to heavy ions. This talk will address the basic mechanisms for laser charge generation in semiconductor materials and review the various SEE analyses for which laser testing can have an interest. Several applications performed at Airbus Defence and Space are detailed.

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